

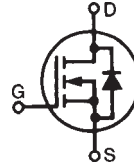
PolarHV™ HiPerFET IXFC 16N50P

Power MOSFET

ISOPLUS220™

(Electrically Isolated Back Surface)

N-Channel Enhancement Mode
Fast Intrinsic Diode
Avalanche Rated



$$V_{DSS} = 500 \text{ V}$$

$$I_{D25} = 10 \text{ A}$$

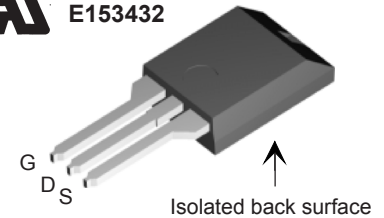
$$R_{DS(on)} \leq 450 \text{ m}\Omega$$

$$t_{rr} \leq 200 \text{ ns}$$

Symbol	Test Conditions	Maximum Ratings	
V_{DSS}	$T_J = 25^\circ\text{C to } 150^\circ\text{C}$	500	V
V_{DGR}	$T_J = 25^\circ\text{C to } 150^\circ\text{C}; R_{GS} = 1 \text{ M}\Omega$	500	V
V_{GS}	Continuous	± 30	V
V_{GSM}	Transient	± 40	V
I_{D25}	$T_C = 25^\circ\text{C}$	10	A
I_{DM}	$T_C = 25^\circ\text{C}$, pulse width limited by T_{JM}	35	A
I_{AR}	$T_C = 25^\circ\text{C}$	10	A
E_{AR}	$T_C = 25^\circ\text{C}$	25	mJ
E_{AS}	$T_C = 25^\circ\text{C}$	750	mJ
dv/dt	$I_S \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 10 \Omega$	10	V/ns
P_D	$T_C = 25^\circ\text{C}$	125	W
T_J		-55 ... +150	$^\circ\text{C}$
T_{JM}		150	$^\circ\text{C}$
T_{stg}		-55 ... +150	$^\circ\text{C}$
T_L	1.6 mm (0.062 in.) from case for 10 s	300	$^\circ\text{C}$
T_{SOLD}	Plastic body for 10 s	260	$^\circ\text{C}$
V_{ISOL}	50/60 Hz, RMS, $t = 1$, leads-to-tab	2500	V~
F_C	Mounting Force	11..65/2.5..15	N/lb
Weight		2	g

ISOPLUS220™ (IXFC)

E153432



G = Gate
S = Source
D = Drain

Features

- † Silicon chip on Direct-Copper-Bond substrate
- High power dissipation
- Isolated mounting surface
- 2500V electrical isolation
- † Low drain to tab capacitance (<35pF)
- † Low $R_{DS(on)}$ HDMOS™ process
- † Rugged polysilicon gate cell structure
- † Unclamped Inductive Switching (UIS) rated
- † Fast intrinsic Rectifier

Applications

- † DC-DC converters
- † Battery chargers
- † Switched-mode and resonant-mode power supplies
- † DC choppers
- † AC motor control

Advantages

- † Easy assembly: no screws, or isolation foils required
- † Space savings
- † High power density
- † Low collector capacitance to ground (low EMI)

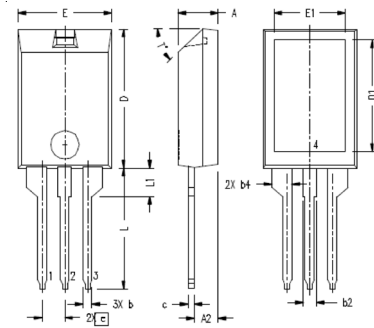
Symbol	Test Conditions ($T_J = 25^\circ\text{C}$ unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 2.5 \text{ mA}$	3.0		5.5 V
I_{GSS}	$V_{GS} = \pm 30 \text{ V}$, $V_{DS} = 0 \text{ V}$			$\pm 100 \text{ nA}$
I_{DSS}	$V_{DS} = V_{DSS}$			5 μA
	$V_{GS} = 0 \text{ V}$ $T_J = 125^\circ\text{C}$			50 μA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = I_T$ (Note 1) Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2\%$			450 $\text{m}\Omega$

Symbol	Test Conditions	Characteristic Values		
		(T _J = 25° C unless otherwise specified)		
		Min.	Typ.	Max.
g_{fs}	V _{DS} = 20 V; I _D = I _T , pulse test	9	16	S
C_{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz		2250	pF
C_{oss}			240	pF
C_{rss}			12	pF
t_{d(on)}	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = I _T R _G = 10 Ω (External)		23	ns
t_r			25	ns
t_{d(off)}			70	ns
t_f			22	ns
Q_{g(on)}	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = I _T		43	nC
Q_{gs}			15	nC
Q_{gd}			12	nC
R_{thJC}			1.0	° C/W
R_{thCS}		0.21		° C/W

Symbol	Test Conditions	Characteristic Values		
		(T _J = 25° C unless otherwise specified)		
		Min.	Typ.	Max.
I_S	V _{GS} = 0 V			16 A
I_{SM}	Repetitive			40 A
V_{SD}	I _F = I _S , V _{GS} = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			1.5 V
t_{rr}	I _F = 16 A, -di/dt = 100 A/μs V _R = 100 V, V _{GS} = 0 V			200 ns
I_{RM}			6	A
Q_{RM}			0.6	μC

Note 1: Test Current I_T = 8 A

ISOPLUS220™ (IXFC) Outline



Note:
Bottom heatsink (Pin 4) is electrically isolated from Pin 1, 2, or 3.

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.157	.197	4.00	5.00
A2	.098	.118	2.50	3.00
b	.035	.051	0.90	1.30
b2	.049	.065	1.25	1.65
b4	.093	.100	2.35	2.55
c	.028	.039	0.70	1.00
D	.591	.630	15.00	16.00
D1	.472	.512	12.00	13.00
E	.394	.433	10.00	11.00
E1	.295	.335	7.50	8.50
e	.100 BASIC		2.55 BASIC	
L	.512	.571	13.00	14.50
L1	.118	.138	3.00	3.50
T*			42.5°	47.5°

Ref: IXYS CO 0177 R0

Fig. 1. Output Characteristics @ 25°C

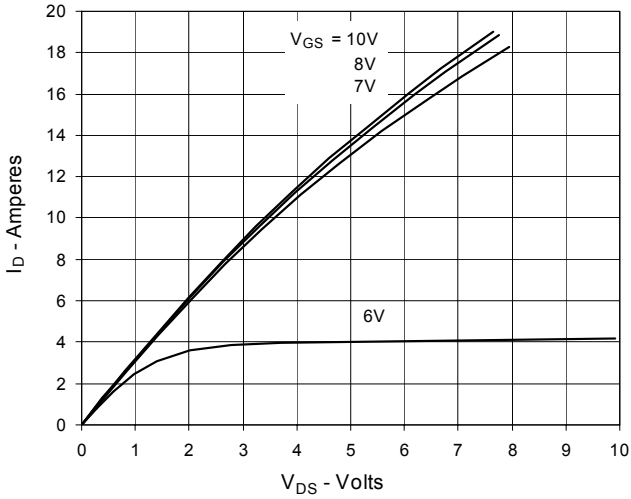


Fig. 2. Output Characteristics @ 125°C

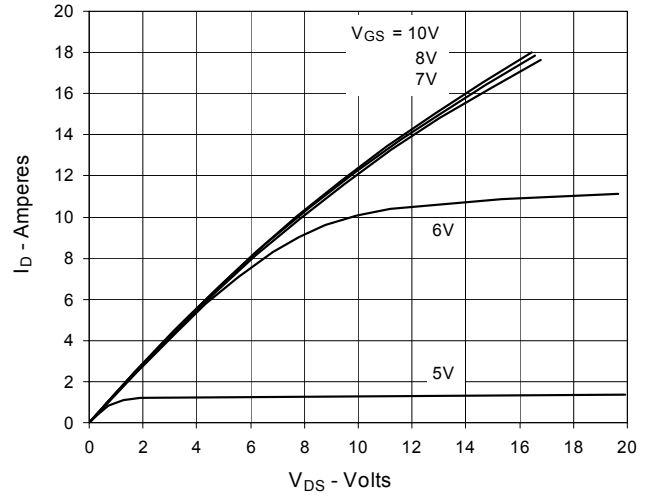


Fig. 3. $R_{DS(on)}$ Normalized to $I_D = 8A$ vs. Junction Temperature

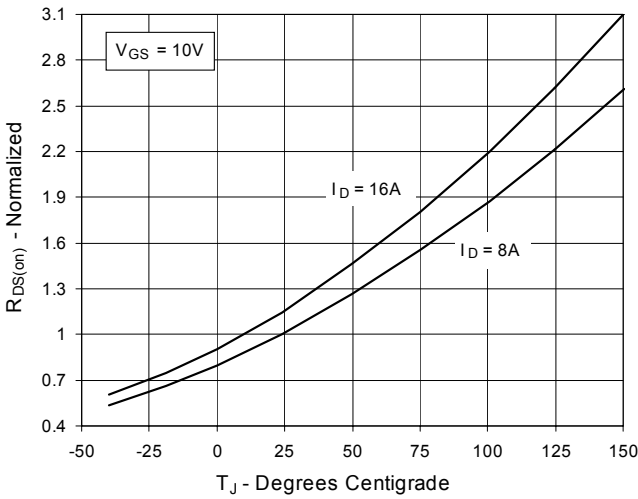


Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 8A$ vs. Drain Current

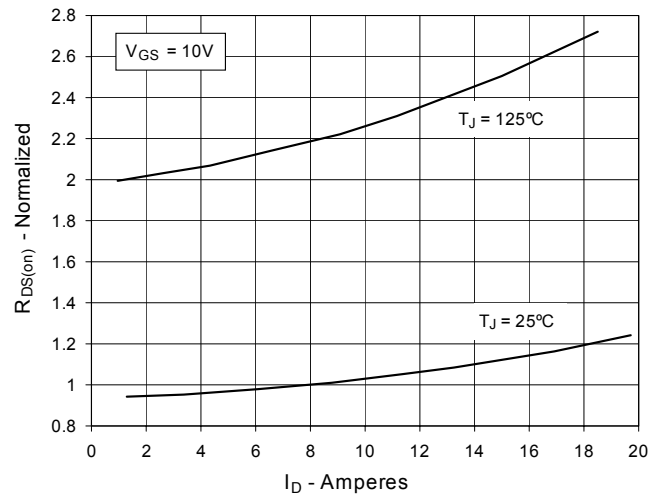


Fig. 5. Maximum Drain Current vs. Case Temperature

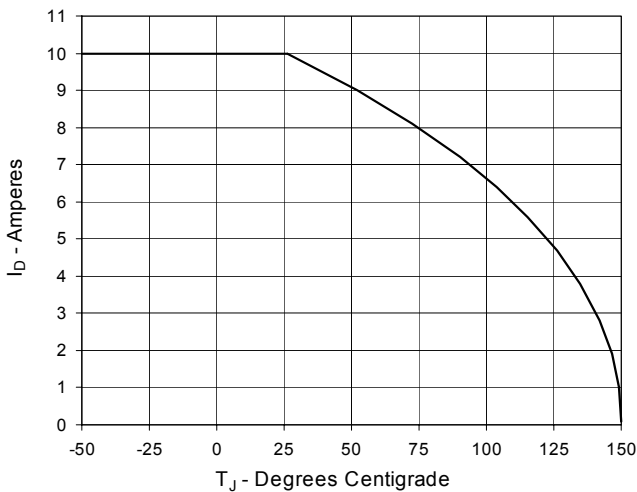


Fig. 6. Input Admittance

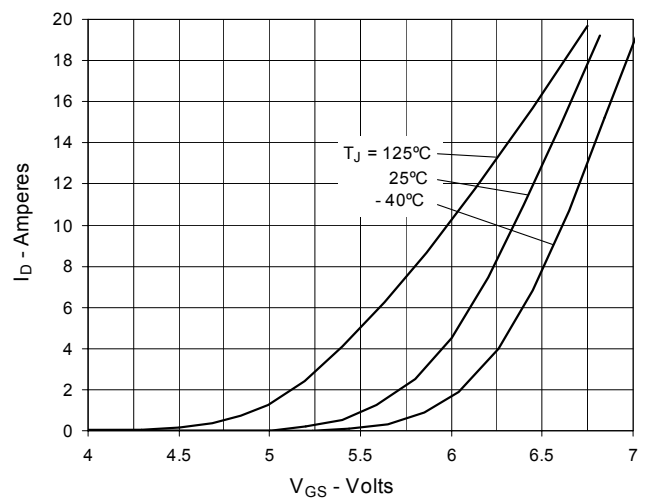


Fig. 7. Transconductance

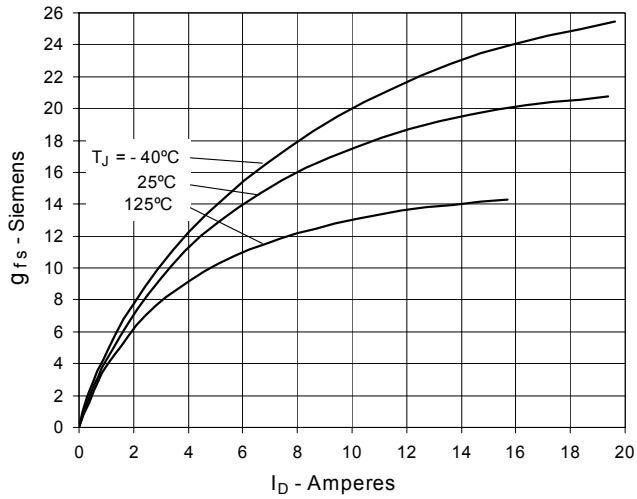


Fig. 8. Forward Voltage Drop of Intrinsic Diode

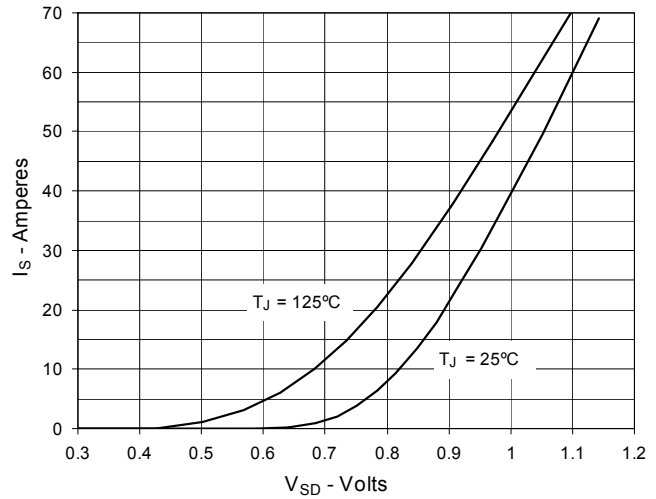


Fig. 9. Gate Charge

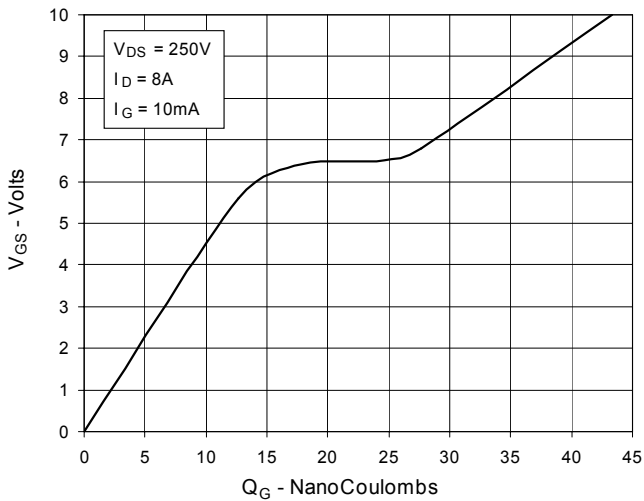


Fig. 10. Capacitance

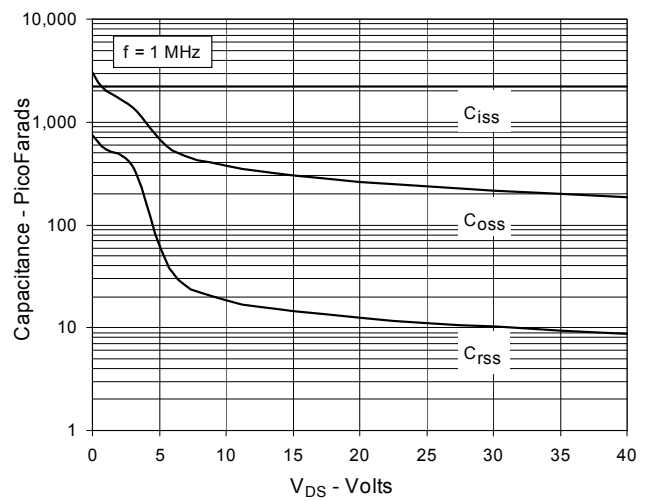


Fig. 11. Forward-Bias Safe Operating Area

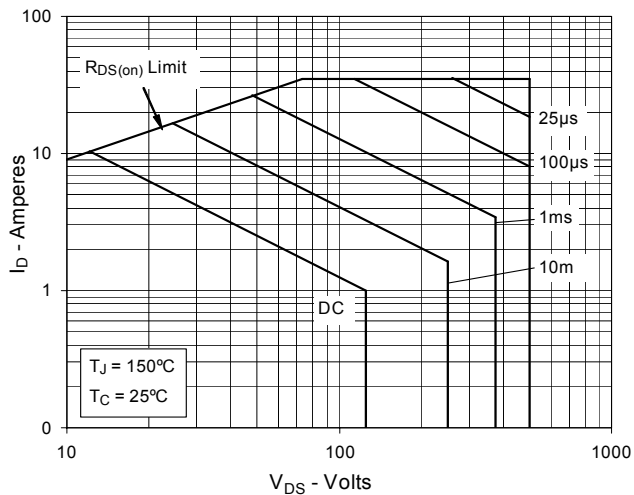


Fig. 12. Maximum Transient Thermal Resistance

